ttomey Docket No. <u>03506/LF</u>

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

plicant(s): Ryouichi YOKOYAMA et al

Serial No. : 10/650,059

Filed : August 27, 2003

For : STRESS MEASUREMENT METHOD

USING X-RAY DIFFRACTION

Art Unit : 2855

Examiner

INFORMATION DISCLOSURE STATEMENT - I

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

SIR:

Submitted herewith are five documents listed on the attached Form PTO/SB/08B. It is respectfully requested that the Examiner return an initialed copy of the attached Form PTO/SB/08B to confirm that the documents listed therein have all been considered and made of record.

Documents 1, 2 and 3 (as listed on the attached Form PTO/SB/08B) are identified and discussed in the "Description of the Related Art" section of the present specification appearing on pages 1-3 of the present specification. An English Abstract is supplied for Document 1. Documents 2 and 3 are in the English language.

Document 1 is also cited in a European Search Report enclosed with the Information Disclosure Statement -II filed concurrently herewith.

Document 2 is also referred to at page 14, lines 2-6 of the present specification.

IFW

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as First Class mail in an envelope addressed to: Commissioner for Patents, P. O. Box 1450. Alexandria, VA 22313-1450. on the date noted below.

Patricia O. Bryson

Dated: June 17, 2004

In the event that this Paper is late filed, and the necessary petition for extension of time is not filed concurrently herewith, please consider this as a Petition for the requisite extension of time, and to the extent not tendered by check attached hereto, authorization to charge the extension fee, or any other fee required in connection with this Paper, to Account No. 06-1378.

The publication edited by Kohra (Document 4 on the attached Form PTO/SB/08B) is discussed on page 10 of the present specification, and is identified at page 10, lines 15-19 of the present specification. A partial English translation of Document 4 is attached to the document.

The Sakurai document (Document 5 on the attached Form PTO/SB/08B) is identified and discussed near the bottom of page 14 of the present specification. A partial English translation of Document 5 is attached to the document.

It is respectfully requested that the Examiner consider the documents submitted herewith and make them of record.

Respectfully submitted,

Leonard Holtz Reg. No. 22,974

Dated: June 17, 2004

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. U.S. Patent and Trademark Office: U.S. DEPARTMENT OF COMMERCE

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	Examiner Signature						Date Considered						

^{*} EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

DATE MAILED:	June	17,	2004	

 $^{^1}$ Unique citation designation number. 2 Place a check here if English translation is attached.